L Numbe			DB	Time stamp
1	3791	716/\$.ccls.	USPAT	2003/03/27 07:14
2	296		USPAT	2003/03/27 07:14
3	73		USPAT	2003/03/27 07:15
4	6	LSI same inspection same (defect or particle) and	USPAT	
		probabilit\$3	USPAI	2003/03/27 07:22
5	12055		LIODAT	
"	12000	One-main. Of twata-main. Of Killing-Ka.in.	USPAT;	2003/03/27 07:24
l			US-PGPUB;	
ļ			EPO; JPO;	
Ì			DERWENT;	
1			IBM_TDB	
-	4	ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in. and hitachi\$.as.	USPAT;	2003/03/27 07:24
			US-PGPUB;	
1			EPO; JPO;	
			DERWENT:	
			IBM_TDB	
6	12024	ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in. and hitachi\$4.as.	USPAT;	2002/02/07 07:05
		The state of the s		2003/03/27 07:25
			US-PGPUB;	
	ļ		EPO; JPO;	
			DERWENT;	
7	40040		IBM_TDB	
7	12016	ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in. and hitachi\$4.as.	USPAT;	2003/03/27 07:25
		and Isi and inspection	US-PGPUB:	
			EPO; JPO;	
			DERWENT:	
			IBM_TDB	
8	5	(ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as.	USPAT;	2002/02/27 07:00
		and Isi and inspection		2003/03/27 07:28
		and tel and mopositori	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
9	40		IBM_TDB	
9	42	(ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as.	USPAT;	2003/03/27 07:28
	İ	and inspection	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
10	37	((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as.	USPAT;	2003/03/27 07:28
		and inspection) not ((ono-m\$.in. or iwata-h\$.in. or	US-PGPUB:	2000/00/27 07.20
		kirino-k\$.in.) and hitachi\$4.as. and Isi and inspection)	EPO; JPO;	
		and the did into position)	DEDINENT.	
		·	DERWENT;	
11	433675	(((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and	IBM_TDB	
• •	100070	hitschied on and inspection) and ((and and in the internal including including including including in the internal including inclu	USPAT;	2003/03/27 07:28
		hitachi\$4.as. and inspection) not ((ono-m\$.in. or iwata-h\$.in.	US-PGPUB;	
		or kirino-k\$.in.) and hitachi\$4.as. and Isi and inspection)) and	EPO; JPO;	
		defect or failure	DERWENT;	
			IBM_TDB	
12	29	(((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and	USPAT;	2003/03/27 07:47
		hitachi\$4.as. and inspection) not ((ono-m\$.in. or iwata-h\$.in.	US-PGPUB:	
		or kirino-k\$.in.) and hitachi\$4.as. and Isi and inspection)) and	EPO; JPO;	
		(defect or failure)	DERWENT;	
	] [	(**************************************		
_	548	((716/19) or (716/21)).CCLS.	IBM_TDB	0000/00/00
_	435	((716/19) of (716/21)).CCLS.	USPAT	2003/03/26 14:32
	1		USPAT	2003/03/26 14:32
-	620	(716/4).CCLS.	USPAT	2003/03/26 14:33
-	985	inspect\$3 same pattern same (defect or failure)	USPAT	2003/03/26 14:33
-	1486	(((716/19) or (716/21)).CCLS.) ((716/2).CCLS.)	USPAT	2003/03/26 14:33
		((716/4).CCLS.)		
•	18	(inspect\$3 same pattern same (defect or failure)) and	USPAT	2003/03/26 15:48
		((((716/19) or (716/21)).CCLS.) ((716/2).CCLS.)		2000/00/20 10,40
		((716/4).CCLS.))		
	4233	wafer near3 inspection	USPAT;	2003/02/26 47:40
				2003/03/26 17:16
			US-PGPUB;	
			EPO; JPO;	
ļ			DERWENT;	
		7:47:49 AM David	IBM_TDB	

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-	754	(wafer near3 inspection) and particle and pattern	USPAT;	2003/03/26 17:17
-	24	(wafer near3 inspection) and particle and pattern and failure near3 probabilit\$3	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/03/26 17:39